

## N-Channel MOSFET

### Features:

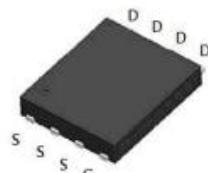
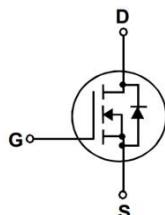
- ◆ RoHS Compliant
- ◆ Low ON Resistance
- ◆ Low Input Capacitance
- ◆ Low Miller Charge
- ◆ Low Input/Output Leakage

### Applications:

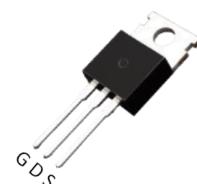
- Lithium - Ion Secondary Batteries  
Load Switch  
DC-DC converters and Off line UPS

$V_{DSS}(\text{Min.})$	40 V
$R_{DS(\text{ON})}(\text{Typ.})$	2.6mΩ
$I_D$	130 A

### Schematic and Package Information:



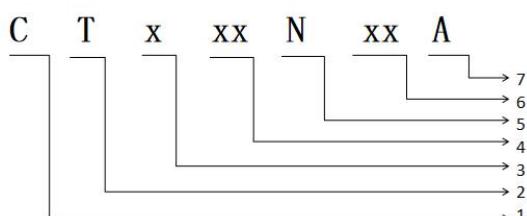
**PDFN5\*6**  
**CSG02N04A**



**TO-220CB**  
**CSP02N04A**

### Marking on the body:

#### MV/LV MOSFET tube naming rules



- 1: CYS for short
- 2: T: Trench S: SGT
- 3: Package
 

F: TO-220F	P: TO-220	D: TO-252
U: TO-251	W: TO-247S/3P	E: SOP-8
G: DFN5*6	K: DFN3.3*3.3	
- 4: RDS(on) Typ
- 5: N: N channel P: P channel
- 6: Maximum breakdown voltage (10% of BVdss)
- 7: Series no.

### Absolute Maximum Ratings

$T_C=25^\circ\text{C}$  unless otherwise specified

Parameter	Symbol	CSx02N04A		Units
		PDFN5*6	TO-220CB	
Drain-to-Source Voltage	$V_{DSS}$	40		V
Gate-to-Source Voltage	$V_{GS}$	$\pm 20$		V
Continuous Drain Current	$I_D$	130		A
Pulsed Drain Current, $V_{GS}@10\text{V}$ (NOTE *1)	$I_{DM}$	380		A
Power Dissipation	$P_D$	96		W
Derating Factor above $25^\circ\text{C}$		22		
Single Pulse Avalanche Energy ( $L=0.5\text{mH}$ )	$E_{AS}$	300		mJ
Peak Diode Recovery $dv/dt$	$dv/dt$	5		V/ns
Maximum Temperature for Soldering	$T_L$	300		$^\circ\text{C}$
Operating Junction and Storage Temperature Range (NOTE *2)	$T_J$ and $T_{STG}$	-55 to 150		

**Thermal Resistance**

Parameter	Symbol	Typ.			Units
		PDFN5*6	TO-220CB		
Junction to Case	$R_{\theta JC}$		1.3		°C/W
Junction to Ambient	$R_{\theta JA}$		60		°C/W

**Electrical Characteristics**  $T_J=25^\circ C$  unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Drain-to-Source Breakdown Voltage	$BV_{DSS}$	40	--	--	V	$V_{GS}=0V, I_D=250\mu A$
Gate Threshold Voltage	$V_{GS(TH)}$	1.0	1.5	2.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Static Drain-to-Source On-Resistance	$R_{DS(ON)}$	--	2.6	3.0	mΩ	$V_{GS}=10V, I_D=20A$
		--	3.4	4.0		$V_{GS}=4.5V, I_D=20A$
		--	--	1	uA	$V_{DS}=40V, V_{GS}=0V$ $T_J=25^\circ C$
Drain-to-Source Leakage Current	$I_{DSS}$	--	--	25		$V_{DS}=40V, V_{GS}=0V$ $T_J=125^\circ C$
Gate-to-Source Forward Leakage	$I_{GSS}$	--	--	+100	nA	$V_{GS}=+20V$
Gate-to-Source Reverse Leakage		--	--	-100		$V_{GS}=-20V$

**Dynamic Characteristics** Essentially independent of operating temperature

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Input Capacitance	$C_{iss}$	--	4711	--	pF	$V_{GS}=0V, V_{DS}=15V$ $f=1.0MHz$
Output Capacitance	$C_{oss}$	--	869	--		
Reverse Transfer Capacitance	$C_{rss}$	--	367	--		
Total Gate Charge	$Q_g$	--	65	--	nC	$I_D=20A, V_D=32V$ $VGS = 5V$
Gate-to-Source Charge	$Q_{gs}$	--	24	--		
Gate-to-Drain ("Miller") Charge	$Q_{gd}$	--	21	--		
Turn-on Delay Time	$t_{d(ON)}$	--	26	--		
Rise Time	$t_{rise}$	--	38	--	ns	$V_D=20V, I_D=30A,$ $V_G=10V R_G=5\Omega$
Turn-Off Delay Time	$t_{d(OFF)}$	--	63	--		
Fall Time	$T_{fall}$	--	20	--		

**Source-Drain Diode Characteristics**  $T_C=25^\circ C$  unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Continuous Drain-Source Diode Forward Current	$I_S$	--	--	120	A	$T_C=25^\circ C$
Pulsed Drain-Source Diode Forward Current	$I_{SM}$	--	--	360		
Diode Forward Voltage	$V_{SD}$	--	--	1.0	V	$I_{SD}=30A, V_{GS}=0V$
Reverse Recovery Time	$t_{rr}$	--	21	--		
Reverse Recovery Charge	$Q_{rr}$	--	10	--	nC	$I_F = I_S$ $di/dt=100A/us$

- Notes:
1.  $T_J = +25^\circ C$  to  $+150^\circ C$ .
  2. Repetitive rating; pulse width limited by maximum junction temperature.
  3. Pulse width < 300μs; duty cycle < 2%.

### Typical Characteristics

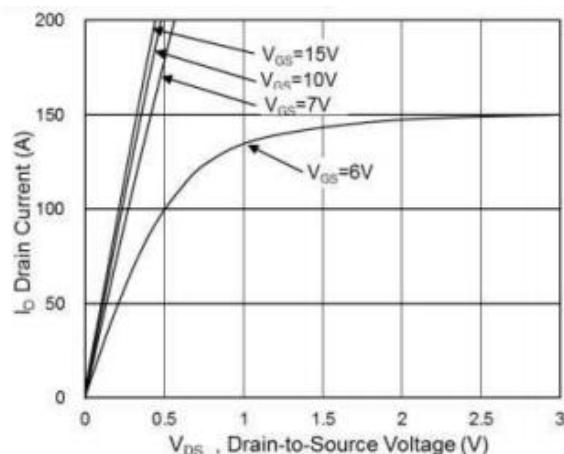


Fig.1 Typical Output Characteristics

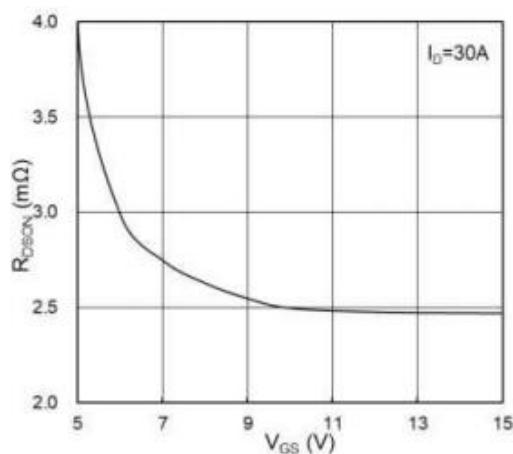


Fig.2 On-Resistance vs. G-S Voltage

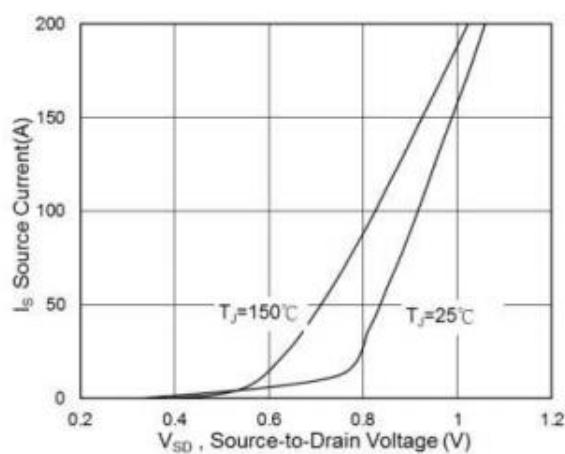


Fig.3 Forward Characteristics of Reverse diode

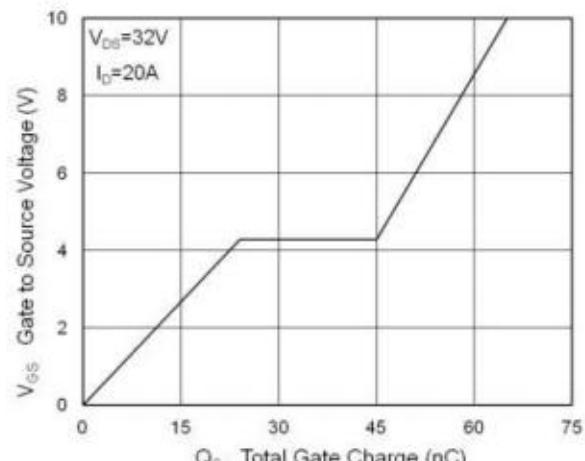


Fig.4 Gate-Charge Characteristics

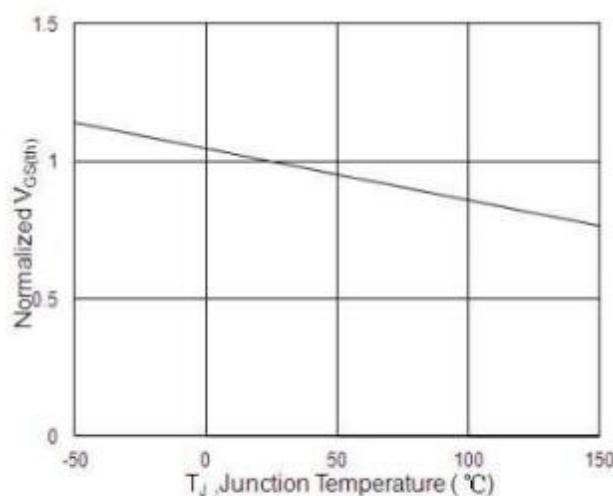


Fig.5 Normalized  $V_{GS(\text{th})}$  vs.  $T_J$

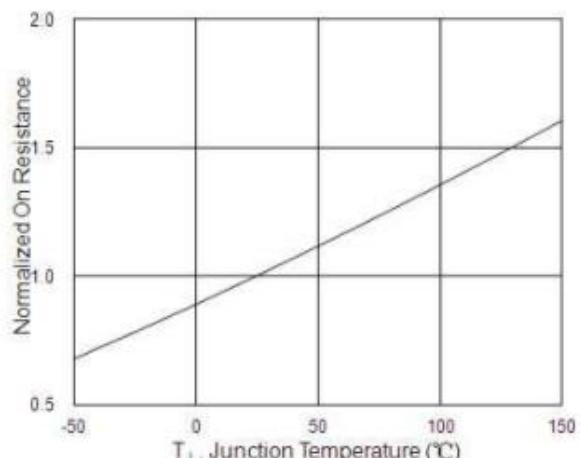
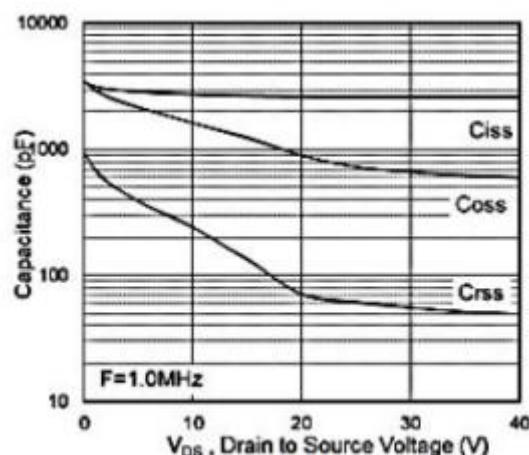
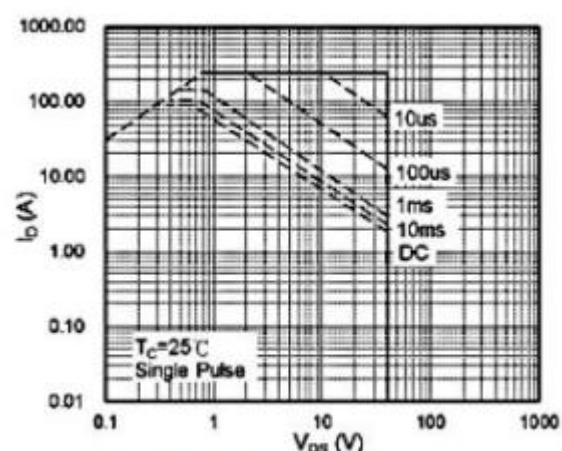
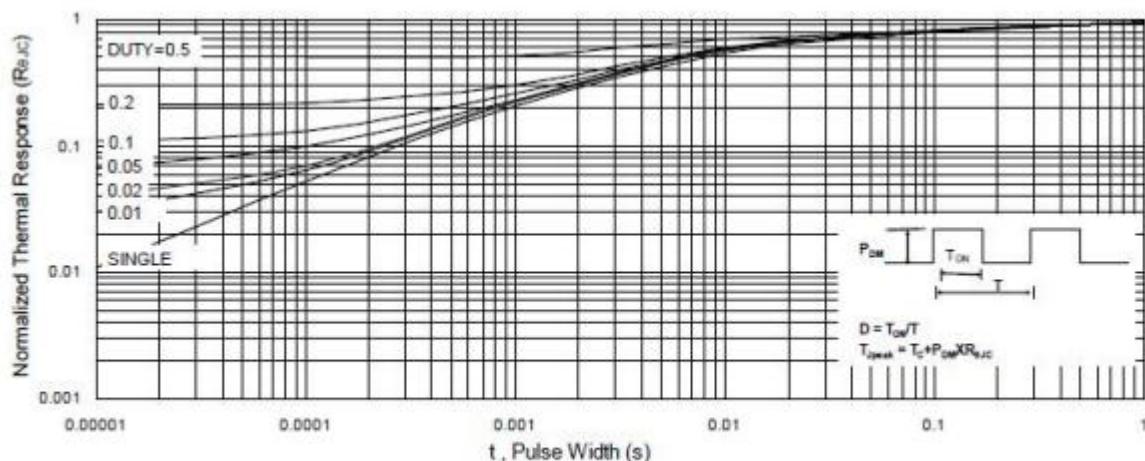
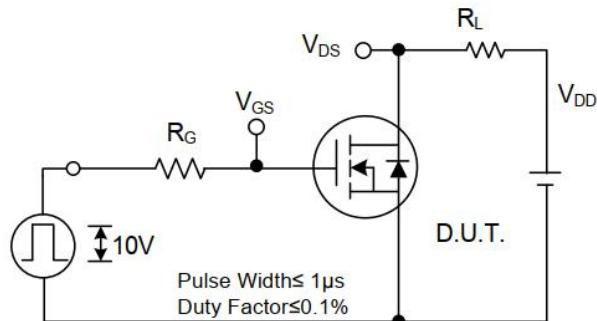


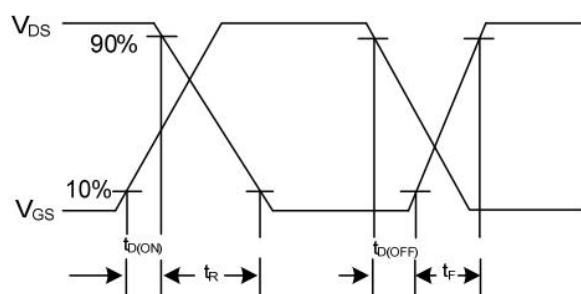
Fig.6 Normalized  $R_{DS(\text{on})}$  vs.  $T_J$


**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

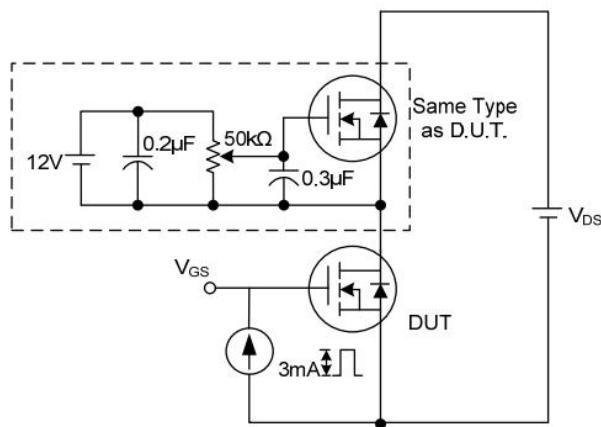
### Test Circuits and Waveform



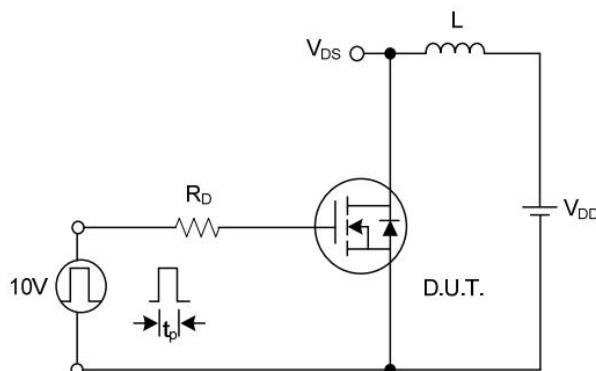
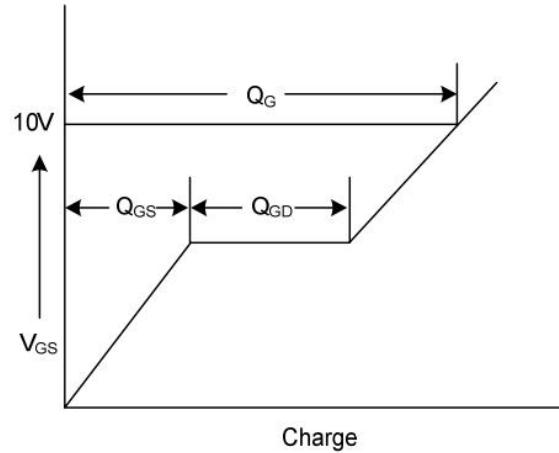
**Switching Test Circuit**



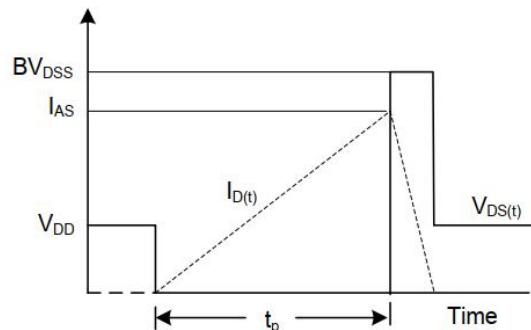
**Switching Waveforms**



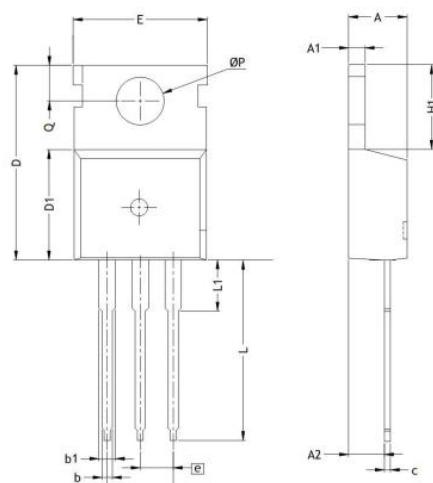
**Gate Charge Test Circuit**



**Unclamped Inductive Switching Test Circuit**

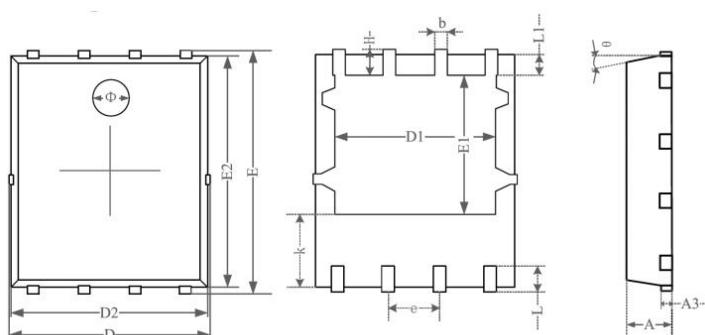


**Unclamped Inductive Switching Waveforms**

**PACKAGE MECHANICAL DATA (Unit: mm):**
**TO-220CB**


DIM	Min.	Max.
A	4.25	4.65
A1	1.25	1.35
A2	2.35	2.55
b	0.7	0.9
b1	1.15	1.75
c	0.45	0.6
D	14.35	15.9
D1	8.8	9.5
E	9.9	10.3
e	Typ 2.54	
e1	Typ 5.08	
H1	6.3	6.5
L	12.85	13.5
L1	2.85	3.25
Q	2.7	2.9
ΦP	3.5	3.9

All Dimensions in millimeter

**DFN5\*6**


DIM	Min.	Max.
A	0.8	1.0
A3	Typ 0.15	
D	4.9	5.1
E	6.0	6.1
D1	3.9	4.1
E1	3.3	3.5
D2	4.8	5.0
E2	5.7	5.8
K	1.2	1.4
b	0.3	0.4
e	Typ 1.27	
L	0.5	0.7
L1	0.4	0.6
H	0.5	0.7
θ	10°	12°
Φ	1.1	1.3

All Dimensions in millimeter

**Statement:**

- ◆ We reserve the right to change the manual without prior notice! Customers should obtain the latest version of the information before placing an order, and verify that the relevant information is complete and up-to-date.
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